

TOSHIBA Transistor Silicon NPN Epitaxial Planar Type

## 2SC3268

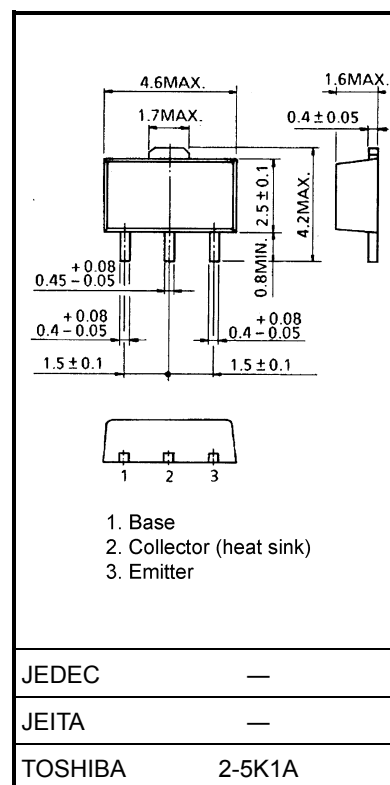
## VHF~UHF Band Low Noise Amplifier Applications

Unit: mm

- NF = 1.7dB,  $|S_{21e}|^2 = 15.0\text{dB}$  ( $f = 500\text{ MHz}$ )
- NF = 2dB,  $|S_{21e}|^2 = 9.5\text{dB}$  ( $f = 1000\text{ MHz}$ )

Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

| Characteristics             | Symbol            | Rating  | Unit             |
|-----------------------------|-------------------|---------|------------------|
| Collector-base voltage      | $V_{CBO}$         | 17      | V                |
| Collector-emitter voltage   | $V_{CEO}$         | 12      | V                |
| Emitter-base voltage        | $V_{EBO}$         | 3       | V                |
| Base current                | $I_B$             | 30      | mA               |
| Collector current           | $I_C$             | 70      | mA               |
| Collector power dissipation | $P_C$             | 300     | mW               |
| Collector power dissipation | $P_C$<br>(Note 1) | 800     | mW               |
| Junction temperature        | $T_j$             | 125     | $^\circ\text{C}$ |
| Storage temperature range   | $T_{stg}$         | -55~150 | $^\circ\text{C}$ |

Note 1: When mounted ceramic substrate of  $250\text{ mm}^2 \times 0.8\text{ mm}$ Microwave Characteristics ( $T_a = 25^\circ\text{C}$ )

Weight: 0.052 g (typ.)

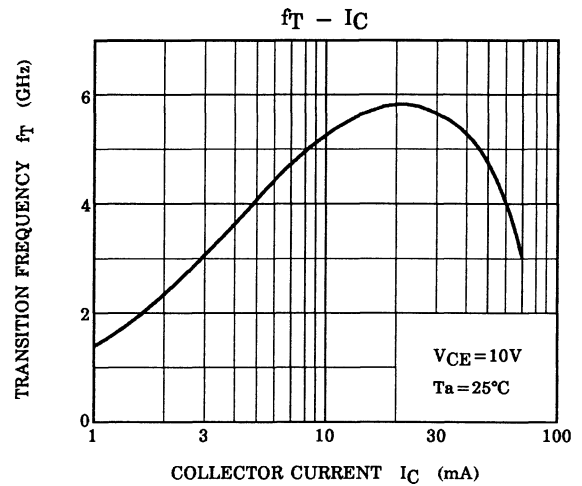
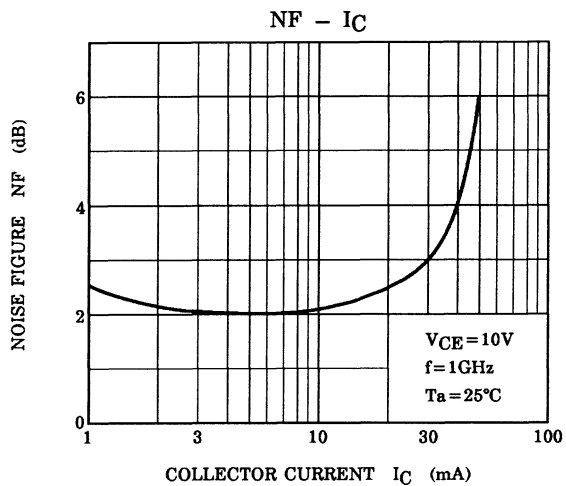
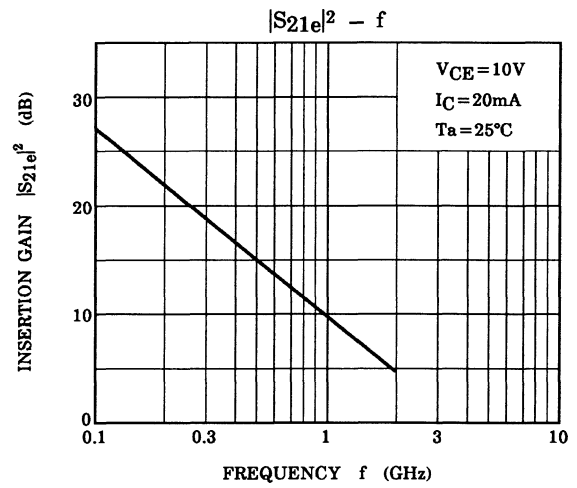
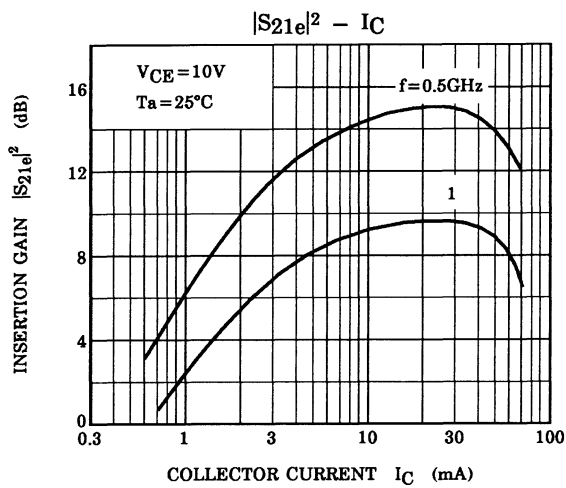
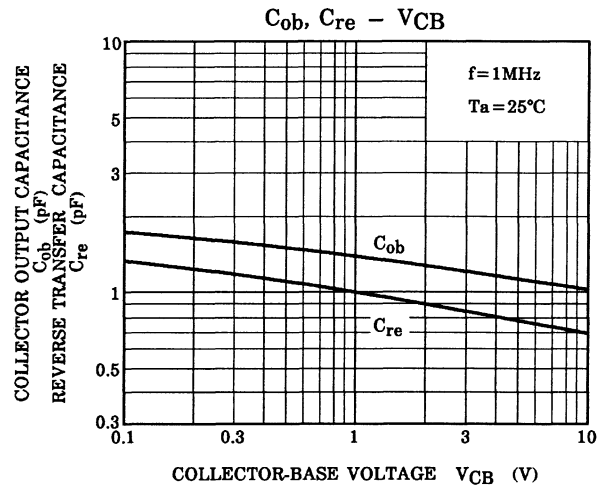
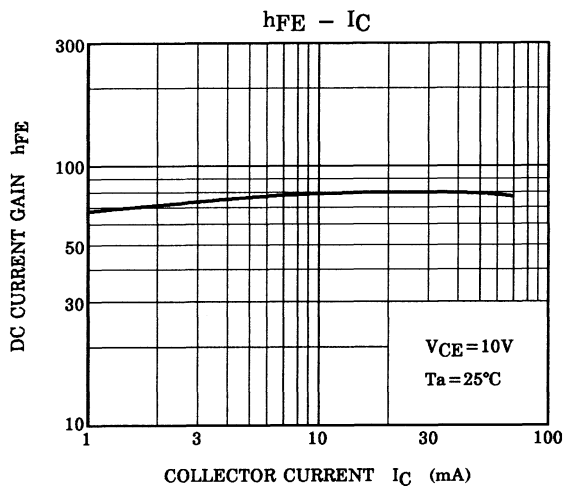
| Characteristics      | Symbol            | Test Condition   | Min | Typ. | Max | Unit |
|----------------------|-------------------|--|-----|------|-----|------|
| Transition frequency | $f_T$             | $V_{CE} = 10\text{ V}$ , $I_C = 20\text{ mA}$                        | —   | 5    | —   | GHz  |
| Insertion gain       | $ S_{21e} ^2 (1)$ | $V_{CE} = 10\text{ V}$ , $I_C = 20\text{ mA}$ , $f = 500\text{ MHz}$ | —   | 15.0 | —   | dB   |
|                      | $ S_{21e} ^2 (2)$ | $V_{CE} = 10\text{ V}$ , $I_C = 20\text{ mA}$ , $f = 1\text{ GHz}$   | —   | 9.5  | —   |      |
| Noise figure         | NF (1)            | $V_{CE} = 10\text{ V}$ , $I_C = 5\text{ mA}$ , $f = 500\text{ MHz}$  | —   | 1.7  | —   | dB   |
|                      | NF (2)            | $V_{CE} = 10\text{ V}$ , $I_C = 5\text{ mA}$ , $f = 1\text{ GHz}$    | —   | 2.0  | —   |      |

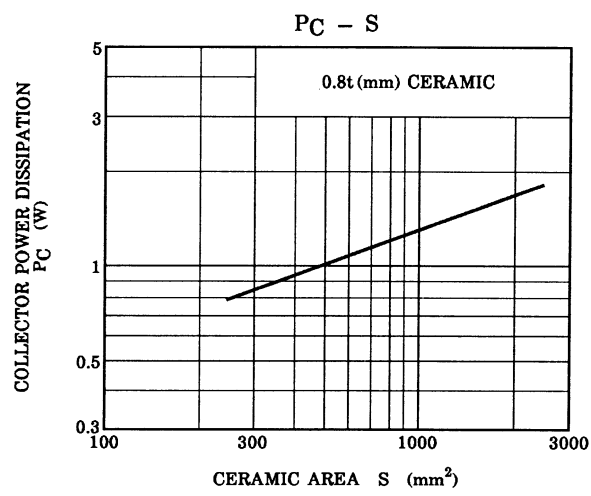
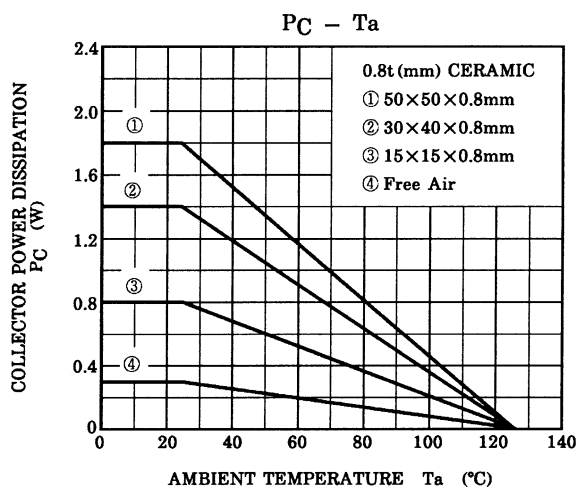
Electrical Characteristics ( $T_a = 25^\circ\text{C}$ )

| Characteristics              | Symbol    | Test Condition   | Min | Typ. | Max | Unit          |
|------------------------------|-----------|--|-----|------|-----|---------------|
| Collector cut-off current    | $I_{CBO}$ | $V_{CB} = 10\text{ V}$ , $I_E = 0$                               | —   | —    | 1   | $\mu\text{A}$ |
| Emitter cut-off current      | $I_{EBO}$ | $V_{EB} = 1\text{ V}$ , $I_C = 0$                                | —   | —    | 1   | $\mu\text{A}$ |
| DC current gain              | $h_{FE}$  | $V_{CE} = 10\text{ V}$ , $I_C = 20\text{ mA}$                    | 25  | —    | —   |               |
| Collector output capacitance | $C_{ob}$  | $V_{CB} = 10\text{ V}$ , $I_E = 0$ , $f = 1\text{ MHz}$ (Note 2) | —   | 1.05 | —   | pF            |
| Reverse transfer capacitance | $C_{re}$  |  | —   | 0.7  | —   | pF            |

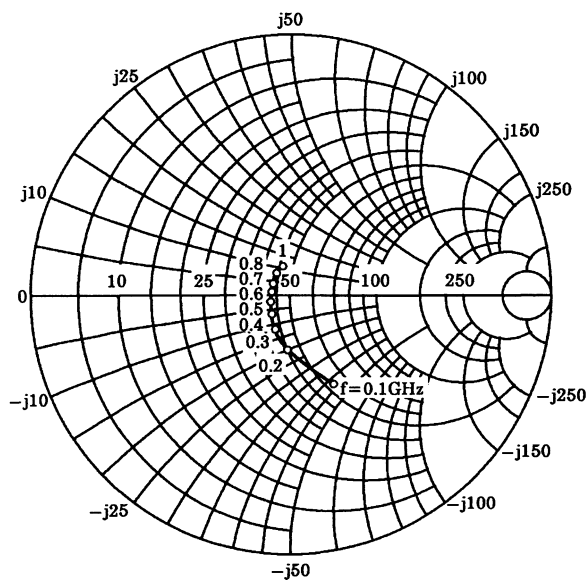
Note 2:  $C_{re}$  is measured by 3 terminal method with capacitance bridge.

## Marking: ME

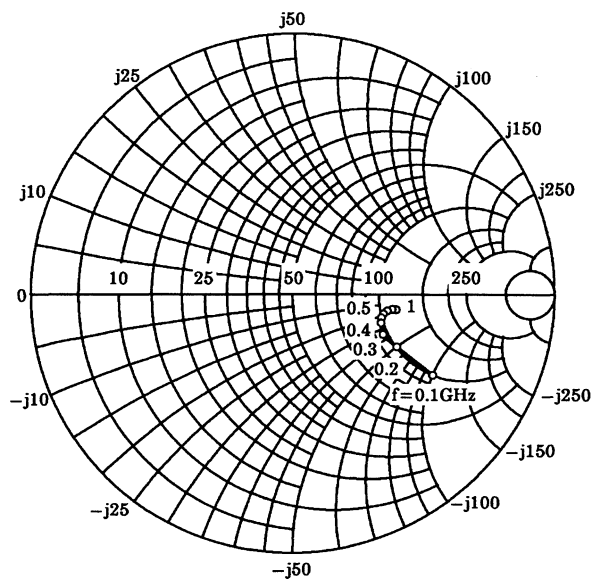




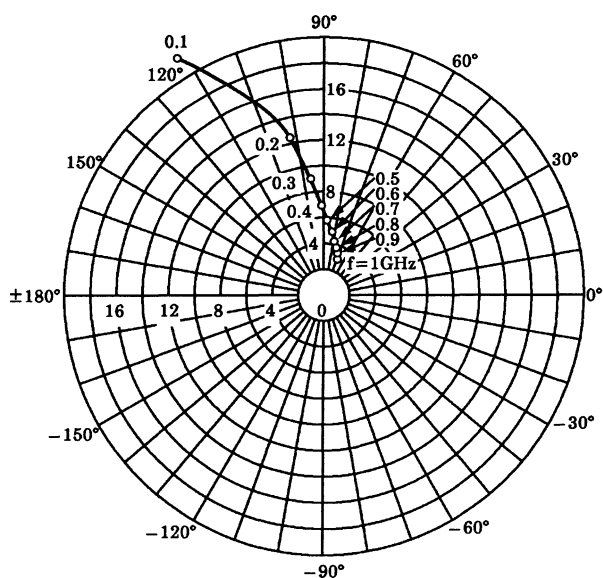
**S<sub>11e</sub>**  
 $V_{CE} = 10V$   
 $I_C = 20mA$   
 $T_a = 25^\circ C$   
 (UNIT :  $\Omega$ )



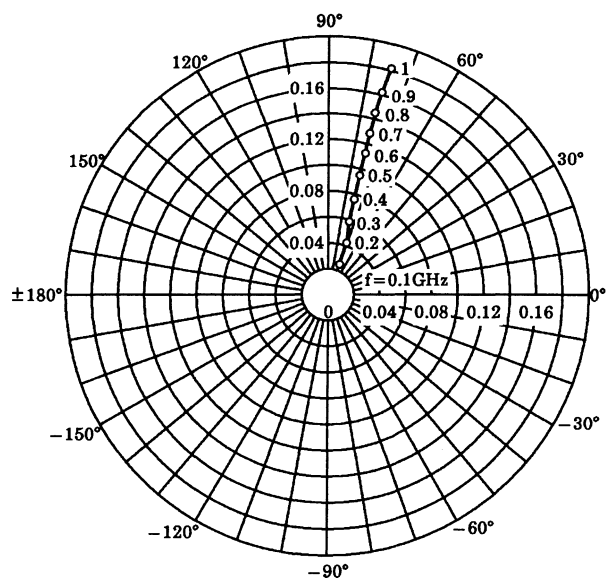
**S<sub>22e</sub>**  
 $V_{CE} = 10V$   
 $I_C = 20mA$   
 $T_a = 25^\circ C$   
 (UNIT :  $\Omega$ )



**S<sub>21e</sub>**  
 $V_{CE} = 10V$   
 $I_C = 20mA$   
 $T_a = 25^\circ C$



**S<sub>12e</sub>**  
 $V_{CE} = 10V$   
 $I_C = 20mA$   
 $T_a = 25^\circ C$



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